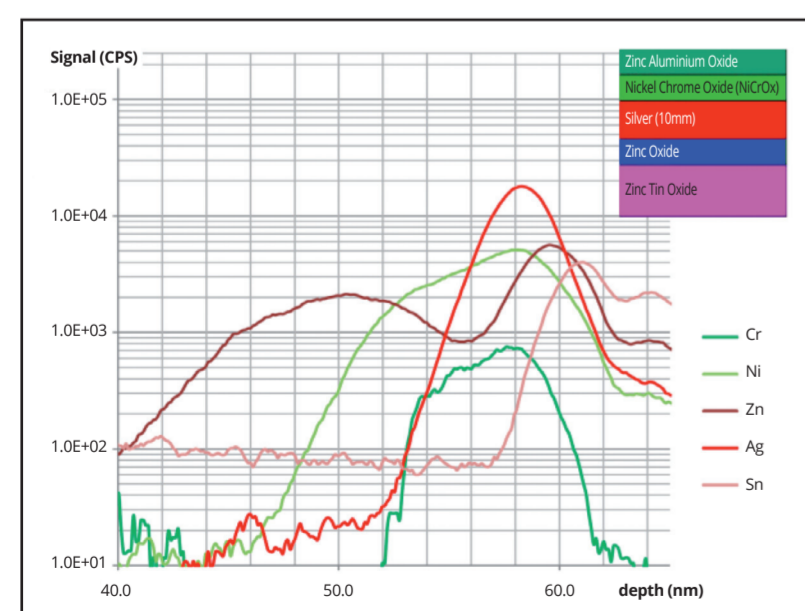




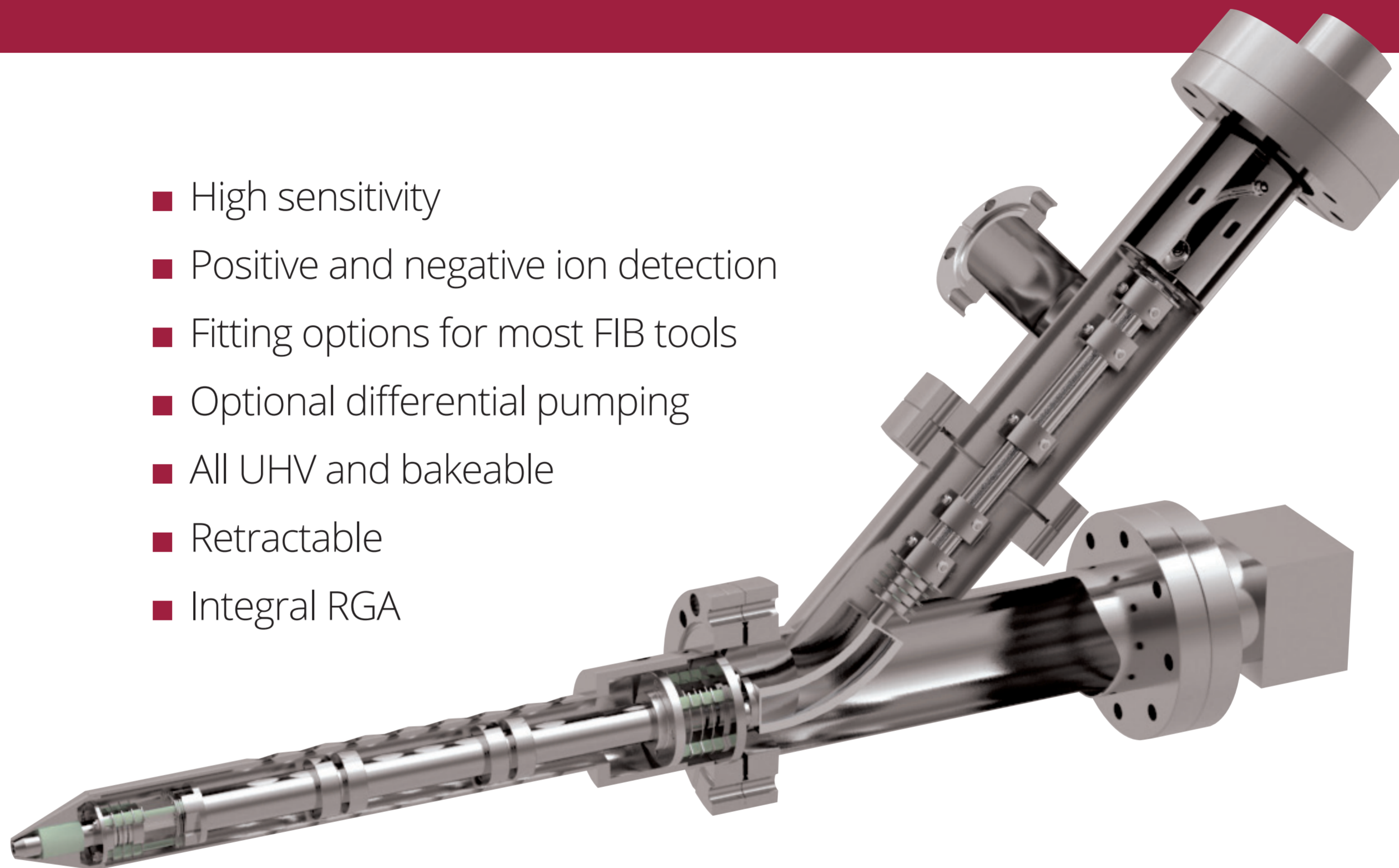
EQS – SIMS for FIB



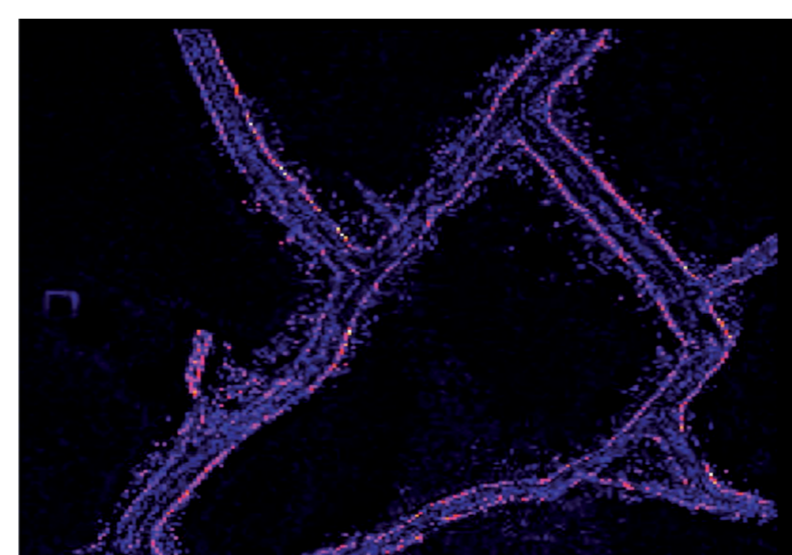
FIB-SIMS depth profile of low emissivity float glass



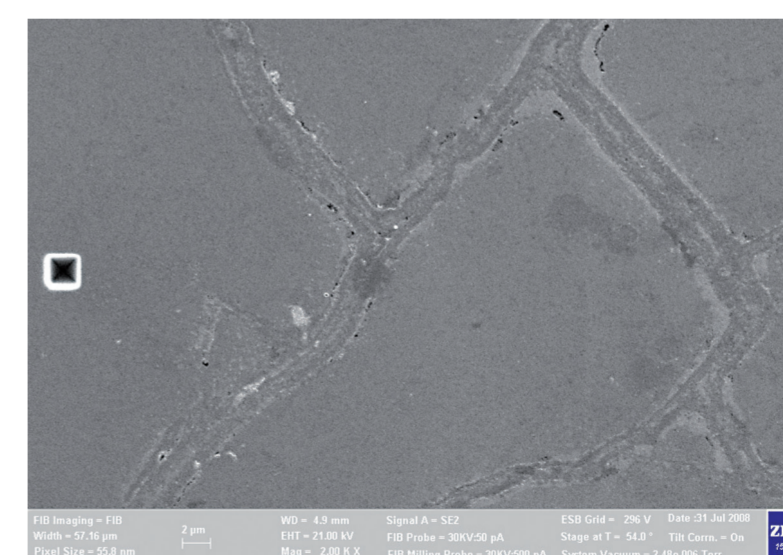
- High sensitivity
- Positive and negative ion detection
- Fitting options for most FIB tools
- Optional differential pumping
- All UHV and bakeable
- Retractable
- Integral RGA



- Imaging
- Mass spectra
- Depth profiling
- 3D mapping

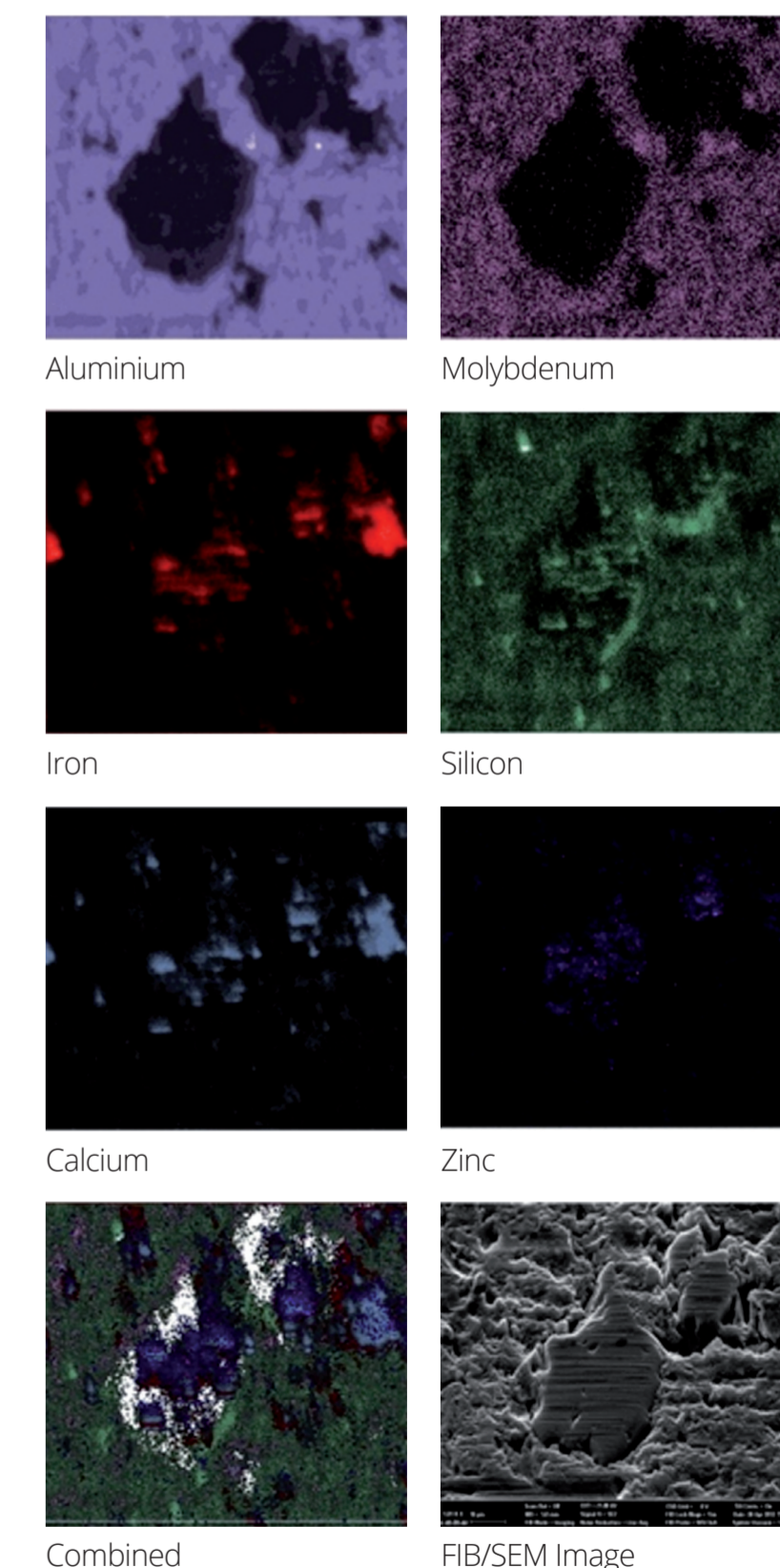


²⁷Al⁺ image showing concentration at grain boundary LaSrCuFe oxide



Sample: Richard Chater, Imperial College London, UK
Instrument: Zeiss Neon, Hiden EQS

Multi Element Map showing the wear characteristics of an Alusil Engine liner



Courtesy of Dr John Walker, National Centre For Advanced Tribology, University of Southampton, UK.
Instrument is ZEISS NVision/Hiden EQS